

In re the Application of

Inventor:

Kiyohito MUKAI et al.

Group Art Unit: 2825

Appln. No.:

10/715,119

Examiner: N. M. Doan

Filed:

November 18, 2003

For:

SEMICONDUCTOR DEVICE LAYOUT INSPECTION METHOD

## AMENDMENT UNDER 37 CFR § 1.116

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

In response to the Office Action dated April 18, 2006, please amend the above-captioned application as follows: